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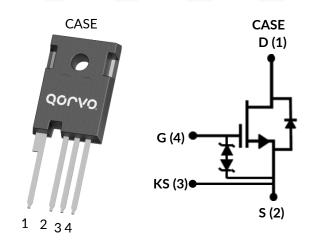
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DATASHEET

UF4SC120009K4SH



Part Number	Package	Marking
UF4SC120009K4SH	TO-247-4L HV	UF4SC120009K4SH



Silicon Carbide (SiC) Cascode JFET -EliteSiC, Power N-Channel, TO-247-4L, 1200 V, 9.1 mohm

Rev. B, January 2025

Description

The UF4SC120009K4SH is a 1200V, $9.1m\Omega$ G4 SiC FET. It is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows use of off-the-shelf gate drivers hence requiring minimal redesign when replacing Si IGBTs, Si superjunction devices or SiC MOSFETs. Available in the TO-247-4L HV package, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads and any application requiring standard gate drive.

Features

- On-resistance R_{DS(on)}: 9.1mΩ (typ)
- Operating temperature: 175°C (max)
- Excellent reverse recovery: Q_{rr} = 615nC
- Low body diode V_{FSD}: 1.09V
- Low gate charge: Q_G = 168nC
- Threshold voltage V_{G(th)}: 4.7V (typ) allowing 0 to 15V drive
- Low intrinsic capacitance
- Kelvin source pin for optimized switching performance
- HV package with 8mm D-S creepage distance
- ESD protected: HBM class 2 and CDM class C3
- AECQ Qualified

Typical applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating





Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V _{DS}		1200	V
Gate-source voltage	V _{GS}	DC	-20 to +20	V
Gale-source voltage	V GS	AC (f > 1Hz)	-25 to +25	V
Continuous drain current ¹	I _D	T _C <100°C	120	А
Pulsed drain current ²	I _{DM}	T _C = 25°C	550	А
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =6.5A	317	mJ
SiC FET dv/dt ruggedness	dv/dt	$V_{DS} \le 800V$	150	V/ns
Power dissipation	P _{tot}	T _C = 25°C	750	W
Maximum junction temperature	T _{J,max}		175	°C
Operating and storage temperature	TJ, T _{STG}		-55 to 175	°C
Max. lead temperature for soldering, 1/8" from case for 5 seconds	TL		250	°C

1. Limited by by bondwires

2. Pulse width t_p limited by $T_{J,max}$

3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Daramatar	Symbol	Test Conditions		L Instein		
Parameter			Min	Тур	Max	Units
Thermal resistance, junction-to-case	$R_{\theta JC}$			0.15	0.20	°C/W

Q0000

Electrical Characteristics (T_J = +25°C unless otherwise specified)

Typical Performance - Static

Devenenter	Sumbol	Test Conditions		L La Sta			
Parameter	Symbol	Test Conditions	Min	Тур	Max	Units	
Drain-source breakdown voltage	BV _{DS}	V _{GS} =0V, I _D =1mA	1200			V	
		V _{DS} =1200V,		E	200		
Total durin lockage summent		V _{GS} =0V, T _J =25°C		5	300		
Total drain leakage current	I _{DSS}	V _{DS} =1200V,		F /		- μΑ	
		V _{GS} =0V, T _J =175°C		56			
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C,		6	20	•	
		V _{GS} =-20V / +20V				μΑ	
	D	V _{GS} =12V, I _D =80A,		0.4	40 /		
		T _J =25°C		9.1 10.6			
Drain-source on-resistance		V _{GS} =12V, I _D =80A,		1/ 0		mΩ	
Drain source on resistance	R _{DS(on)}	т _л =125°С		16.9			
		V _{GS} =12V, I _D =80A,	23.3			1	
		т _ј =175°С		23.5			
Gate threshold voltage	V _{G(th)}	V_{DS} =5V, I_{D} =10mA	4	4.7	6	V	
Gate resistance	R _G	f=1MHz, open drain		0.8	1.5	Ω	

Typical Performance - Reverse Diode

Denseration	Course la sel	Test Conditions		Units		
Parameter	Symbol	Test Conditions	Min	Min Typ		Units
Diode continuous forward current ¹	I _s	T _C < 100°C			120	А
Diode pulse current ²	I _{S,pulse}	T _C =25°C			550	А
		V _{GS} =0V, I _S =40A,		1.00	1 45	v
Forward voltage	V	T_=25°C		1.09	1.45	
Forward voltage	V _{FSD}	V _{GS} =0V, I _S =40A,		1.31		
		т _ј =175°С		1.51		
Reverse recovery charge	Q _{rr}	V _{DS} =800V, I _S =80A,		615		nC
Reverse recovery charge		V_{GS} =0V, $R_{G_{EXT}}$ =2 Ω		015		IIC
Reverse recovery time	t _{rr}	di/dt=2600A/μs,		48		ns
	۲r	TJ=25°C		10		115
Reverse recovery charge	Q _{rr}	V _{DS} =800V, I _S =80A,		724		nC
	Υrr	V_{GS} =0V, $R_{G_{EXT}}$ =2 Ω		/ 27		
Reverse recovery time	t _{rr}	di/dt=2600A/μs,		55		ns
	۲r	T _J =150°C				115





Typical Performance - Dynamic

		T I C I'I'		Value		L Lucitur	
Parameter	Symbol	Test Conditions	Min	Тур	Max	Units	
Input capacitance	C _{iss}	- V _{DS} =800V, V _{GS} =0V -		7218			
Output capacitance	C _{oss}	f=100kHz		204		рF	
Reverse transfer capacitance	C _{rss}			0.2			
Effective output capacitance, energy related	C _{oss(er)}	V _{DS} =0V to 800V, V _{GS} =0V		265		pF	
Effective output capacitance, time related	C _{oss(tr)}	V _{DS} =0V to 800V, V _{GS} =0V		528		pF	
C _{OSS} stored energy	E _{oss}	V _{DS} =800V, V _{GS} =0V		85		μJ	
Total gate charge	Q _G	V _{DS} =800V, I _D =80A,		168			
Gate-drain charge	Q_{GD}	$V_{\rm DS} = 000$, $I_{\rm D} = 00$, $V_{\rm GS} = 0$ V to 15V		28		nC	
Gate-source charge	Q_{GS}	V _{GS} - 0V to 15V		50			
Turn-on delay time	t _{d(on)}			40		- ns	
Rise time	t _r	Notes 4 and 5, V_{DS} =800V, I_D =80A, Gate Driver =0V to +15V, $R_{G,EXT}$ =2 Ω , inductive Load, FWD: same device with		37			
Turn-off delay time	t _{d(off)}			81			
Fall time	t _f			16			
Turn-on energy including R _s energy	E _{ON}			1656		μ	
Turn-off energy including R _s energy	E _{OFF}	V_{GS} = 0V and R_{G} = 2 Ω , RC		255			
Total switching energy	E _{TOTAL}	snubber: R _s =5Ω and C _s =440pF,		1911			
Snubber R_s energy during turn-on	E _{RS_ON}	C _S -440pF, T _I =25°C		19.5			
Snubber R_s energy during turn-off	E_{RS_OFF}			76.5			
Turn-on delay time	t _{d(on)}			36			
Rise time	t _r	Notes 4 and 5,		42		1	
Turn-off delay time	$t_{d(off)}$	$V_{DS}=800V, I_{D}=80A, Gate$ Driver =0V to +15V, $R_{G,EXT}=2\Omega, \text{ inductive Load,}$ FWD: same device with $V_{GS}=0V \text{ and } R_{G}=2\Omega, RC$		85		ns	
Fall time	t _f			18		1	
Turn-on energy including R _s energy	E _{ON}			1940		-	
Turn-off energy including R _s energy	E _{OFF}			283			
Total switching energy	E _{TOTAL}	snubber: $R_s = 5\Omega$ and		2223		μ	
Snubber R _s energy during turn-on	E _{RS_ON}	– C _s =440pF, T ₁ =150°C		18		1	
Snubber R_s energy during turn-off	E_{RS_OFF}			71]	

4. Measured with the switching test circuit in Figure 26.

5. In this table, the switching energies (turn-on energy, turn-off energy and total energy) presented include the device RC snubber energy losses.



Typical Performance - Dynamic (continued)

Deventer	Cumphel	Test Conditions	Value			
Parameter	Symbol	lest Conditions	Min	Тур	Max	- Units
Turn-on delay time	t _{d(on)}			40		
Rise time	t _r	Notes 5 and 6,		30		
Turn-off delay time	t _{d(off)}	V _{DS} =800V, I _D =80A, Gate		81		ns
Fall time	t _f	Driver =0V to +15V, $R_{G,EXT}=2\Omega$, inductive Load, FWD: UJ3D1250K2, RC snubber: $R_s=5\Omega$ and $C_s=440pF$, $T_J=25^{\circ}C$		13		
Turn-on energy including R _s energy	E _{ON}			918		
Turn-off energy including R _s energy	E _{OFF}			250		μ -
Total switching energy	E _{TOTAL}			1168		
Snubber R _s energy during turn-on	E _{RS_ON}			18		
Snubber R _s energy during turn-off	E _{RS_OFF}			113		
Turn-on delay time	t _{d(on)}			36		
Rise time	t _r	Notes 5 and 6,		34		
Turn-off delay time	t _{d(off)}	V _{DS} =800V, I _D =80A, Gate		85		ns
Fall time	t _f	Driver =0V to +15V,		14		
Turn-on energy including R _s energy	E _{ON}	$\begin{array}{c c} R_{G,EXT}=2\Omega, \text{ inductive Load,} \\ FWD: UJ3D1250K2, RC \\ snubber: R_{S}=5\Omega \text{ and} \\ C_{S}=440pF, \\ T_{J}=150^{\circ}C \end{array}$		1040		
Turn-off energy including R _s energy	E _{OFF}			280		
Total switching energy	E _{TOTAL}			1320		μJ
Snubber R _s energy during turn-on	E _{RS_ON}			16.5		
Snubber R _s energy during turn-off	E _{RS_OFF}			110		1

6. Measured with the switching test circuit in Figure 26 where the high-side switch Q1 is replaced with the diode and no RC snubber is applied for the diode.

Typical Performance Diagrams

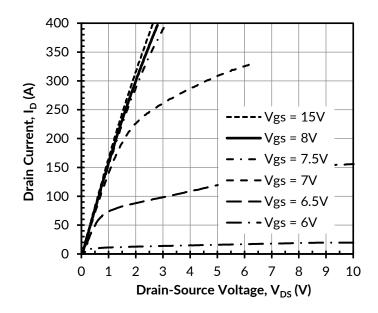
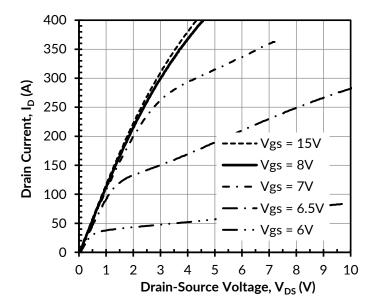


Figure 1. Typical output characteristics at $T_J = -55^{\circ}C$, tp < 250 μ s



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Figure 2. Typical output characteristics at T_J = 25°C, tp < 250 μ s

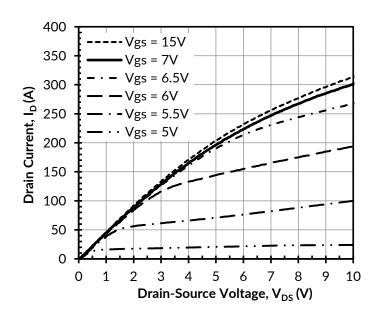


Figure 3. Typical output characteristics at $T_J = 175^{\circ}C$, tp < 250 μ s

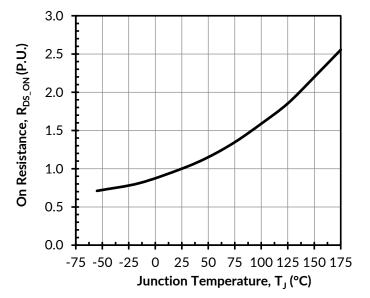


Figure 4. Normalized on-resistance vs. temperature at V_{GS} = 12V and I_{D} = 80A



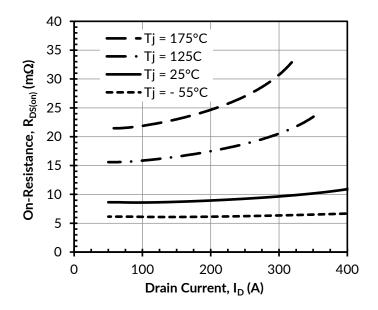


Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

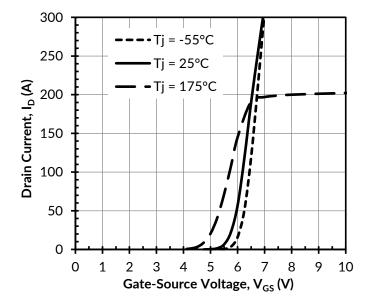


Figure 6. Typical transfer characteristics at V_{DS} = 5V

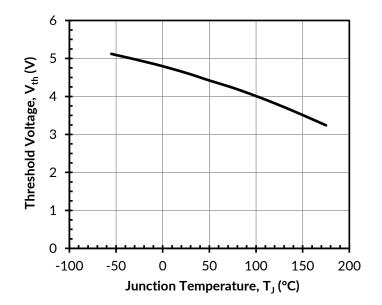


Figure 7. Threshold voltage vs. junction temperature at V_{DS} = 5V and I_D = 10mA

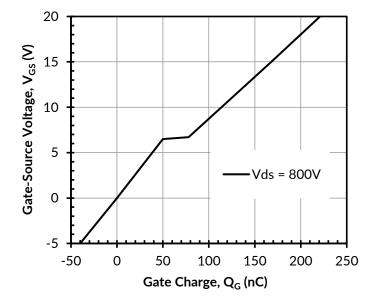
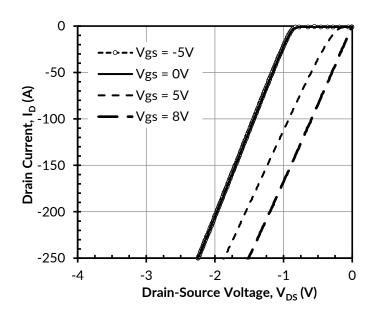


Figure 8. Typical gate charge at $I_D = 80A$

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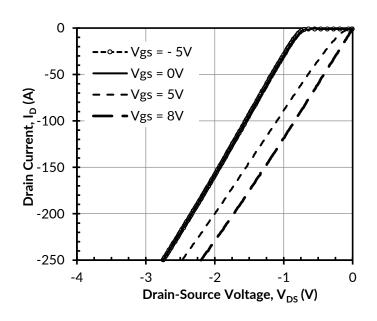


Figure 9. 3rd quadrant characteristics at $T_J = -55^{\circ}C$

Figure 10. 3rd quadrant characteristics at $T_J = 25^{\circ}C$

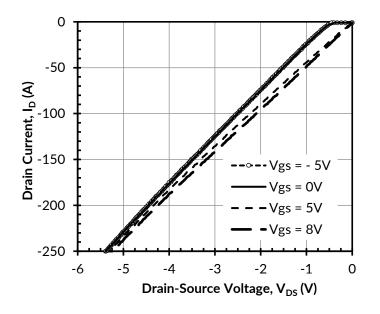


Figure 11. 3rd quadrant characteristics at T_J = 175°C

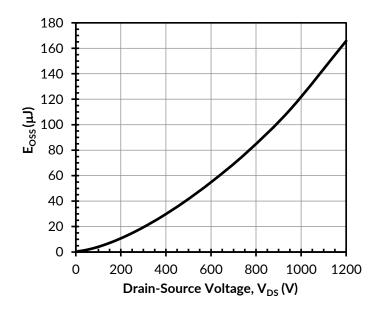


Figure 12. Typical stored energy in C_{OSS} at V_{GS} = 0V



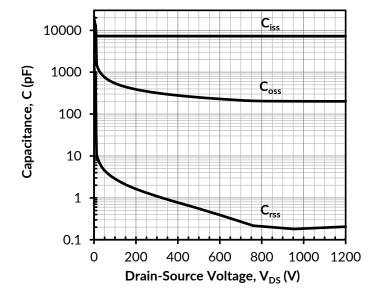


Figure 13. Typical capacitances at f = 100kHz and V_{GS} = 0V

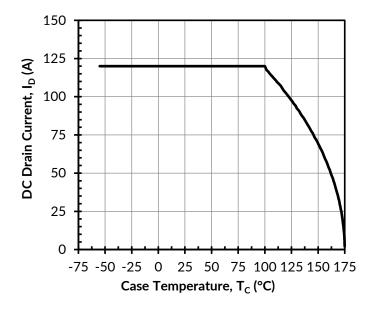


Figure 14. DC drain current derating

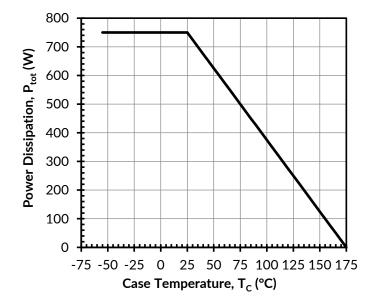


Figure 15. Total power dissipation

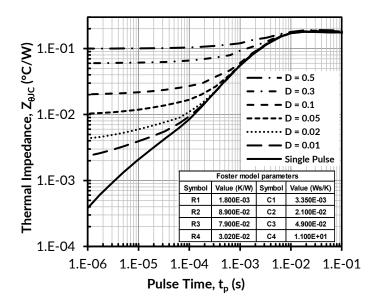


Figure 16. Maximum transient thermal impedance

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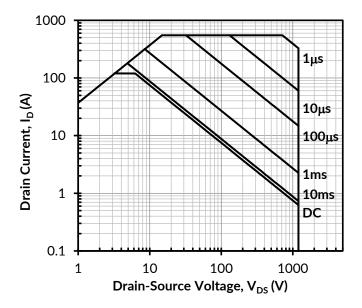


Figure 17. Safe operation area at $T_{\rm C}$ = 25°C, D = 0, Parameter $t_{\rm p}$

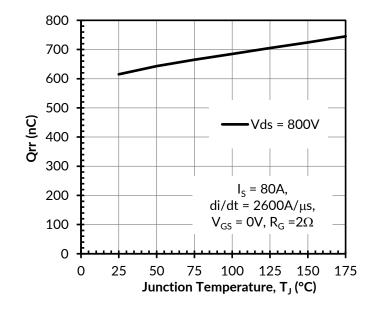


Figure 18. Reverse recovery charge Qrr vs. junction temperature

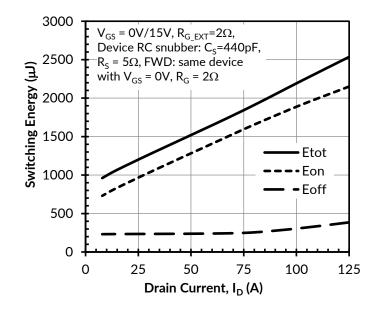


Figure 19. Clamped inductive switching energy vs. drain current at V_{DS} = 800V and T_J = 25°C

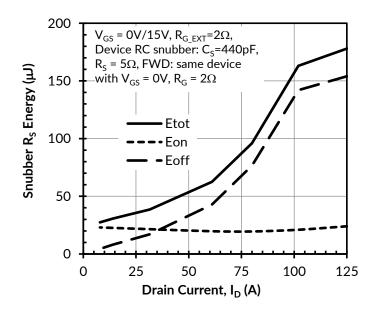


Figure 20. RC snubber energy loss vs. drain current at V_{DS} = 800V and T_J = 25°C



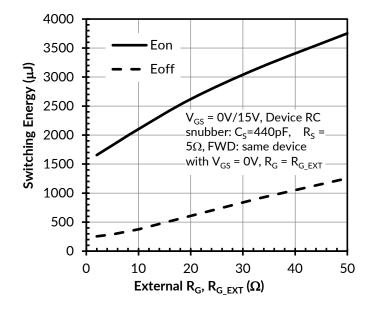


Figure 21. Clamped inductive switching energies vs. $R_{G,EXT}$ at V_{DS} = 800V, I_D = 80A, and T_J = 25°C

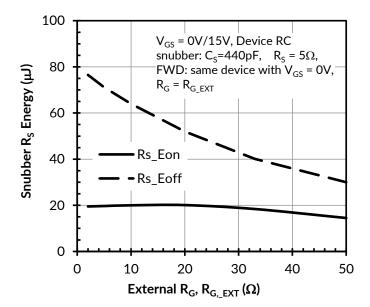


Figure 22. RC snubber energy losses vs. $R_{G,EXT}$ at V_{DS} = 800V, I_D = 80A, and T_J = 25°C

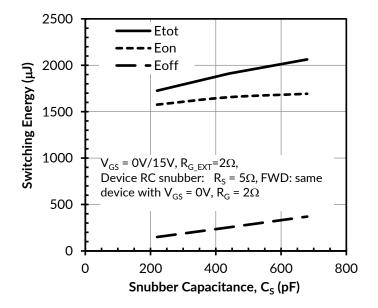


Figure 23. Clamped inductive switching energies vs. snubber capacitance C_S at V_{DS} = 800V, I_D = 80A, and T_J = 25°C

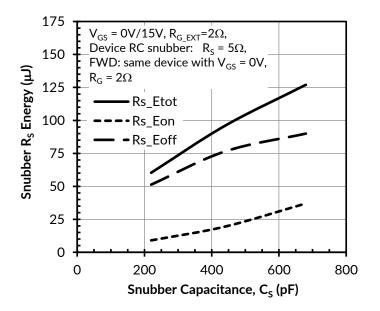
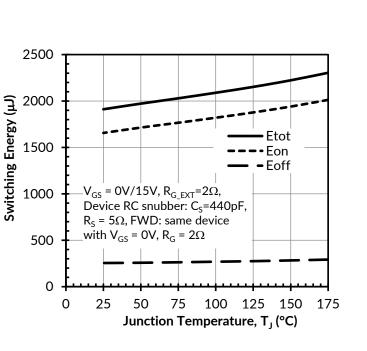
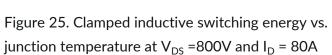
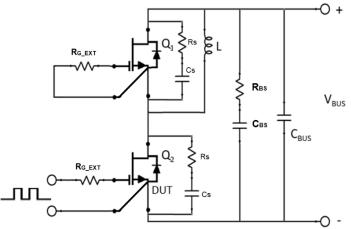


Figure 24. RC snubber energy losses vs. snubber capacitance C_S at V_{DS} = 800V, I_D = 80A, and T_J = 25°C







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Figure 26. Schematic of the half-bridge mode switching test circuit. Note, a bus RC snubber ($R_{BS} = 5\Omega$, $C_{BS}=100$ nF) is used to reduce the power loop high frequency oscillations.



Applications Information

SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_{rr}) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see https://www.qorvo.com/innovation/power-solutions/sic-power/sic-fet-design-tips.

A snubber circuit with a small $R_{(G)}$, or gate resistor, provides better EMI suppression with higher efficiency compared to using a high $R_{(G)}$ value. There is no extra gate delay time when using the snubber circuitry, and a small $R_{(G)}$ will better control both the turn-off $V_{(DS)}$ peak spike and ringing duration, while a high $R_{(G)}$ will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high $R_{(G)}$, while greatly reducing $E_{(OFF)}$ from mid-to-full load range with only a small increase in $E_{(ON)}$. Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the Qorvo website at https://www.qorvo.com/innovation/power-solutions/sic-power/sic-fet-design-tips.

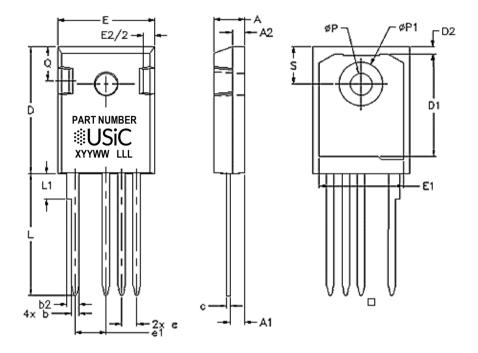
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TO-247-4L PACKAGE OUTLINE, PART MARKING AND TUBE SPECIFICATIONS

PACKAGE OUTLINE



DIM	INC	HES	ES MILLIME		
	MIN	MAX	MIN	MAX	
A	0.185	0.209	4.7	5.31	
A1	0.087	0.102	2.21	2.59	
A2	0.059	0.098	1.5	2.49	
b	0.039	0.055	0.99	1.4	
b2	0.065	0.094	1.65	2.39	
С	0.015	0.035	0.38	0.89	
D	0.819	0.845	20.8	21.46	
D1	0.515	-	13.08	-	
D2	0.02	0.053	0.51	1.35	
E	0.61	0.64	15.49	16.26	
e	0.100 BSC		2.54 BSC		
e1	0.19	0.21	4.83	5.33	
E1	0.53	-	13.46	-	
E2	0.14	0.16	3.56	4.06	
L	0.78	0.8	19.81	20.32	
L1	-	0.177	-	4.5	
ФР	0.14	0.144	3.56	3.66	
ΦΡ1	0.278	0.291	7.06	7.39	
Q	0.212	0.244	5.38 6.2		
S	0.243 BSC		6.17 BSC		



TO-247-4L PACKAGE OUTLINE, PART MARKING AND TUBE SPECIFICATIONS

PART NUMBER = REFER TO DS_PN DECODER FOR DETAILS X = ASSEMBLY SITE

YY = YEAR WW = WORK WEEK LLL = LOT ID

PACKING TYPE

ANTI-STATIC TUBE

QUANTITY /TUBE : 30 UNITS

XYYWW

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